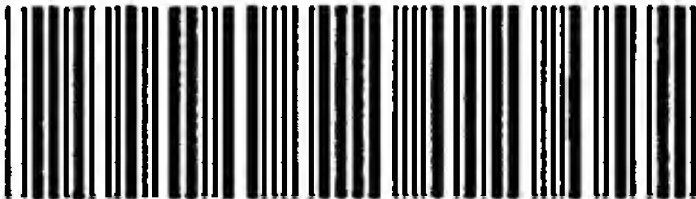


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/673,932	HU, TECK	
	Examiner	Art Unit	
	Khai M. Nguyen	2617	

SEARCHED			
Class	Subclass	Date	Examiner
see	previous		KN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
see previous		KN